

Digital stress compensation for stacked InAs/GaAs QDs solar cells

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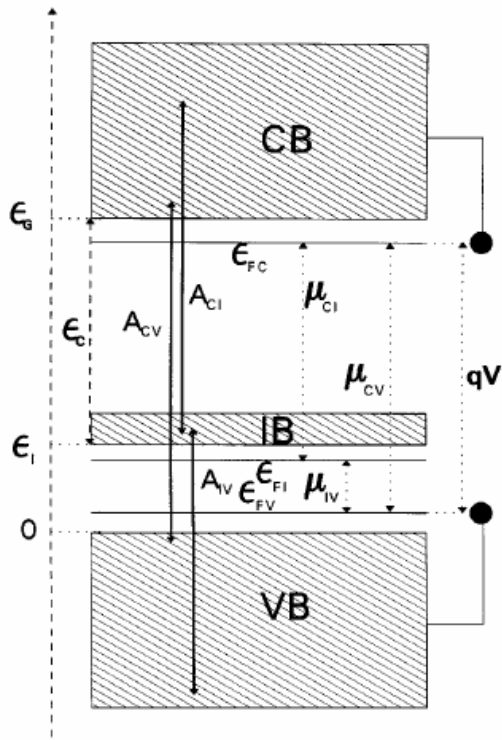
TNT 2008 OVIEDO

Outline

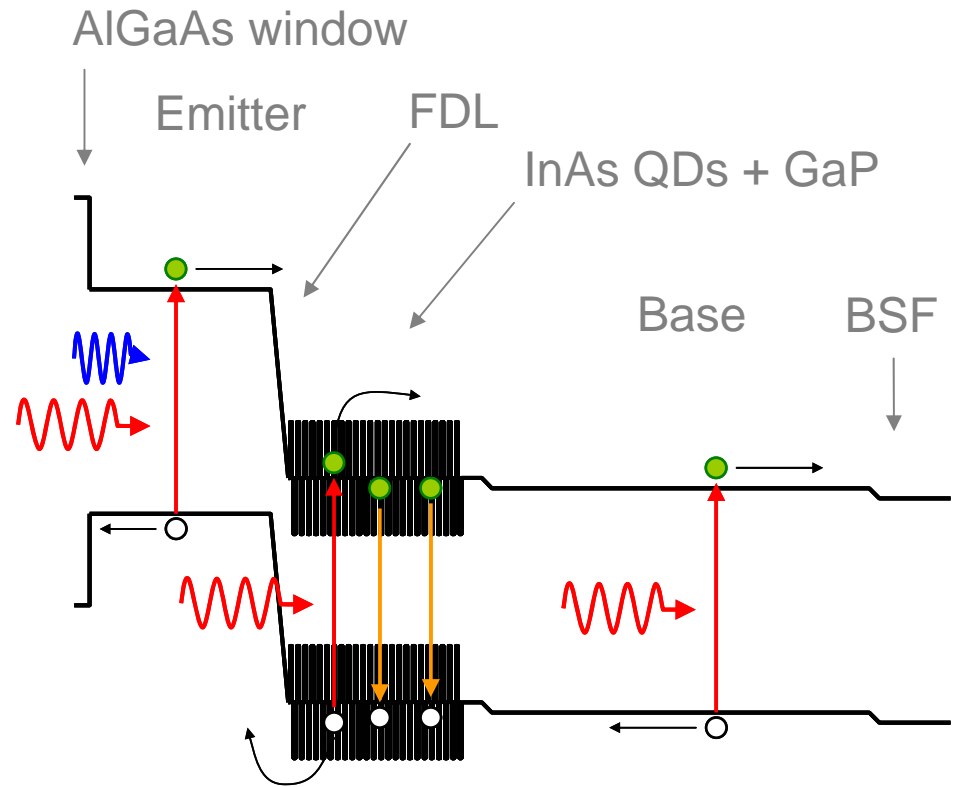
- 1. Introduction: GaAs/InAs QDs Solar Cell**
- 2. MBE growth for zero average stress:
 Digital stress compensation with GaP monolayers**
- 3. Structural quality: XRD, AFM and TEM**
- 4. Optical properties: photoluminescence and
 photocurrent**
- 5. Conclusions**

GaAs InAs QDs Solar Cell:

A basic device to study the physics of the IB concept



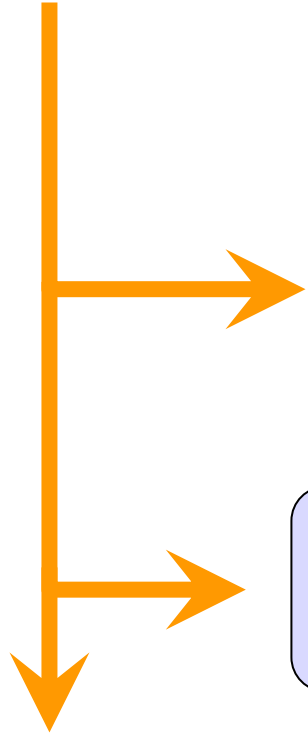
Band diagram of a solar cell with an intermediate band.



Objective:

Increase the light absorption of QDs based devices

- LEDs
- Lasers
- Barriers photodetectors
- Solar cells
- ...



Increase the QD density per layer

Increase density → Reduce size → Increase transition energy

Increase the number of QDs layers

⊗ Devices usually have a limited active region thickness

Increase the density of QDs layers

⊗ Increase of defects due to excessive strain

→ **Strain compensation**

→ InAs/GaAs QDs with GaP strain compensation monolayers

Reference	N° Layers	QDs (InAs)	SC layers	Spacer	Application
Nuntawong et al. Appl. Phys. Lett. 85 , 3050 (2004)	10	3 ML	8 ML (In _{0.36} Ga _{0.64} P) 8 ML (In _{0.30} Ga _{0.70} P)	19 nm	General (MOCVD)
Nuntawong et al. Appl. Phys. Lett. 86 , 193115 (2005)	5	3 ML	2 ML (GaP) 4 ML " 6 ML " 8 ML "	17 nm 17.58 nm 18.12 nm 18.66 nm	Lasers (MOCVD)
Tatebayachi et al. Appl. Phys. Lett. 88 , 221107 (2006)	6	2.6 ML	6 ML GaP	27 nm	Lasers (MOCVD)
Fu et al. Appl. Phys. Lett. 91 , 073515 (2007)	10	5.7 ML (In _{0.5} Ga _{0.5} As)	1.83 ML GaP	50 nm	QD IR photodetectors (MOCVD)
Lever et al. J. Appl. Phys. 95 5710 (2004)	3	5.8 ML (In _{0.5} Ga _{0.5} As)	1.83 ML GaP	30 nm	General (MOCVD)
Oshima et al. Photovoltaic Energy Conversion, Conference Record of the 2006 IEEE 4th World Conference on Volume 1, May 2006 Page(s):158 - 161	20	2 ML	40 nm GaN _{0.005} As _{0.995}	40 nm	Solar Cells (H-MBE)
This Work	50	2 ML	1 + 1 ML GaP	18 nm	Solar Cells (MBE)

Stack design for zero stress condition

Strain components due to a biaxial stress

$$\begin{cases} \varepsilon_{xx} = \varepsilon_{yy} = \varepsilon = \frac{a_0 - a_1}{a_0} \\ \varepsilon_{zz} = \nu \varepsilon_{xx} \\ \varepsilon_{xy} = \varepsilon_{xz} = \varepsilon_{yz} = 0 \end{cases}$$

Strain energy density in the layer

$$U = \left[C_{11} + C_{12} - \frac{2C_{12}^2}{C_{11}} \right] \varepsilon^2 = A \varepsilon^2$$

Matrix:

$$a_{(\text{GaAs})} = 2.83 \text{ \AA}$$

QDs:

$$a_{(\text{InAs})} = 3.03 \text{ \AA}$$

Compensation:

$$a_{(\text{GaP})} = 2.73 \text{ \AA}$$

$$\frac{n_{\text{GaP}}}{n_{\text{InAs}}} \approx 0.9$$

10 x InAs QDs (18 nm)
+ 72 nm GaAs + QD (AFM)

- ↔ Reference sample
- ↔ Strain compensated sample

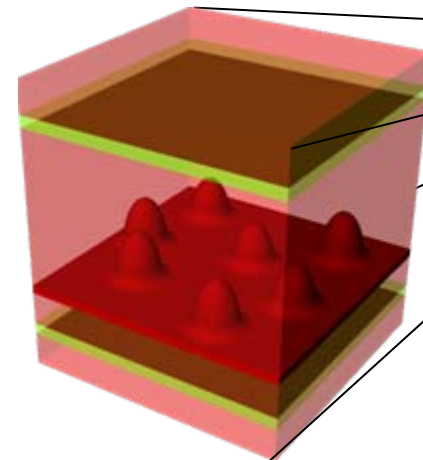
Average strain energy density $U_{av} \approx \frac{A_1 \varepsilon_1^2 n_1 a_1 + A_2 \varepsilon_2^2 n_2 a_2}{n_1 a_1 + n_2 a_2}$

Strain relation between two layers pseudomorphically grown on GaAs

Zero stress condition

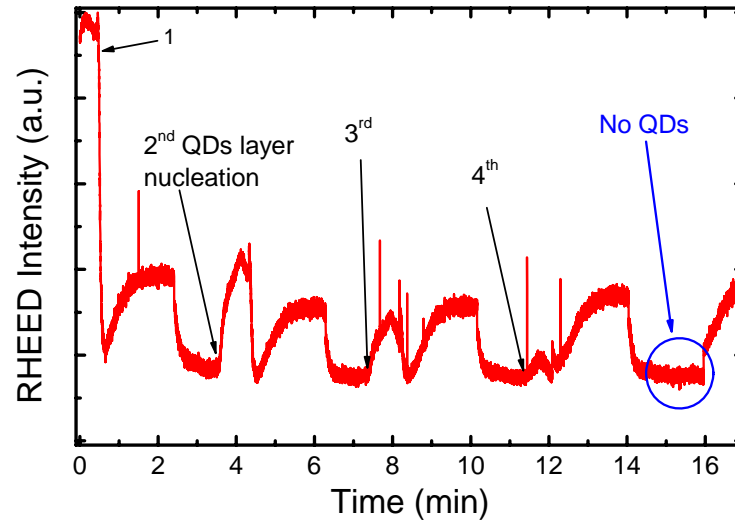
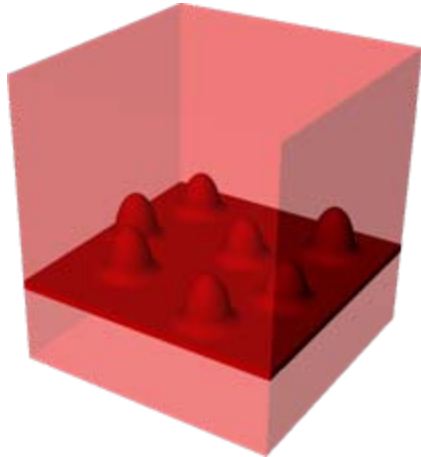
$$\frac{n_1}{n_2} = - \frac{A_2 \varepsilon_2}{A_1 \varepsilon_1}$$

33.3 \AA GaAs
1 ML GaP
126 \AA GaAs
15.3 \AA GaAs
1 ML GaP

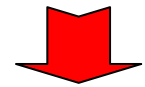


MBE growth sequence

Without GaP SC layers

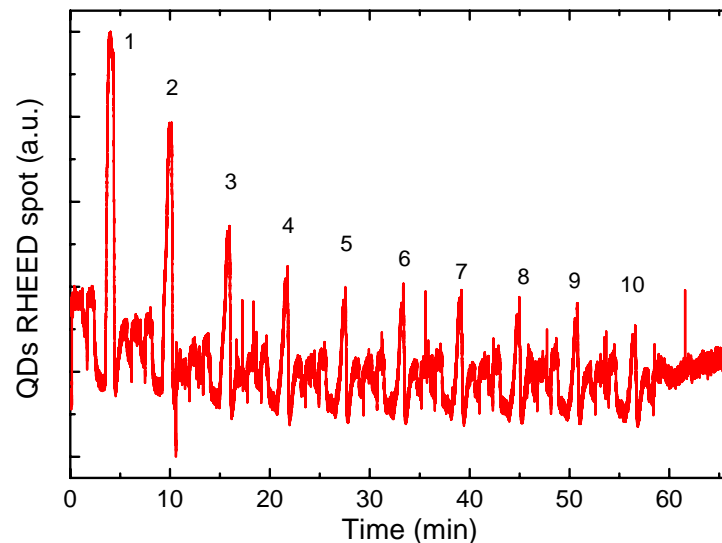
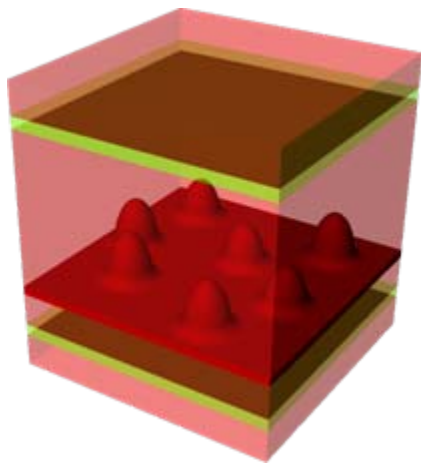


No QDs nucleation
observed by
RHEED beyond
the 4th layer

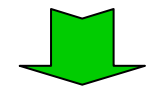


Accumulated strain
creates too many
defects

With GaP SC layers



Uniform QDs
nucleation time

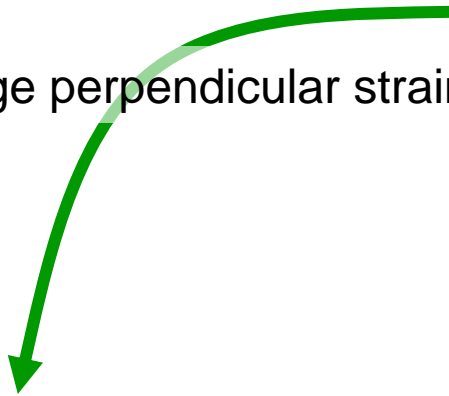


Evidence of correct
strain
compensation

Structural characterization: XRD

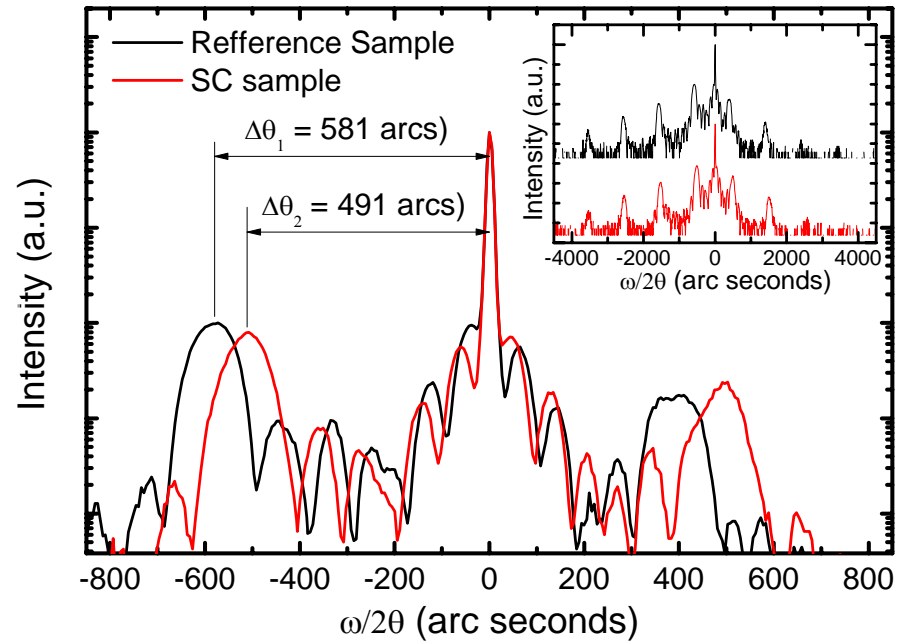
Average perpendicular strain

$$\langle \varepsilon_t \rangle = \frac{\sin^2 \theta_0 - \Delta \theta}{\sin \theta_0}$$



	No SC	SC
$\Delta \theta$ (arcs)	581	491
$\langle \varepsilon_t \rangle$	0.004368	0.003679
Relative strain Reduction (%)	--	19

Symmetric (004) reflection



- GaP thickness
 < nominal thickness
- GaAs_(1-x)P_x alloy
- Both

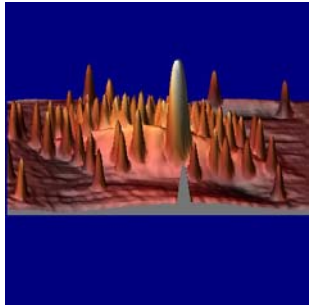
10 stacked layers of InAs QDs Characterization by AFM

Without Strain Compensating Layers

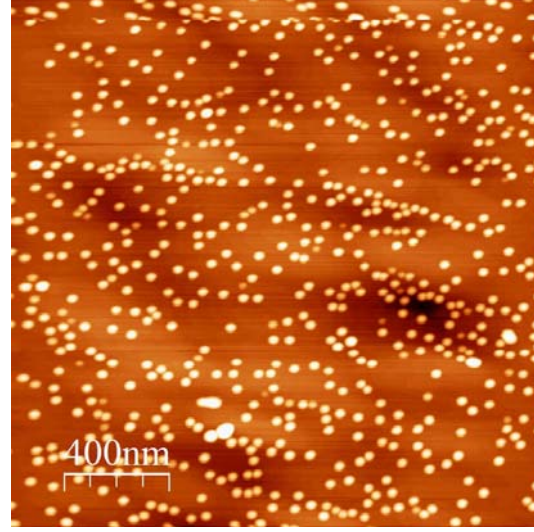
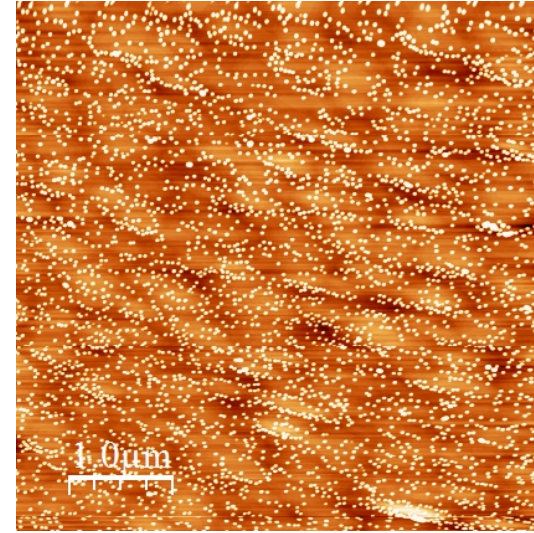
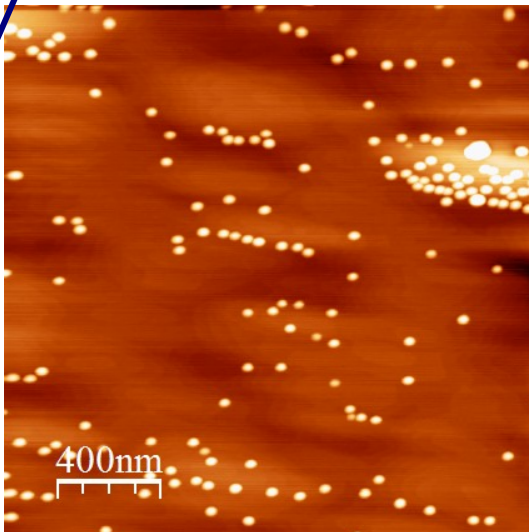
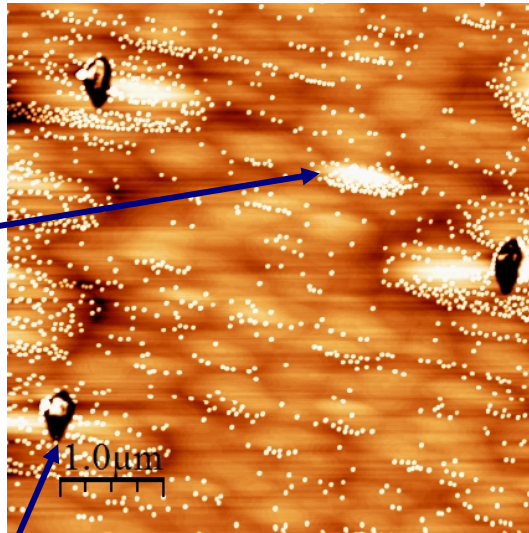
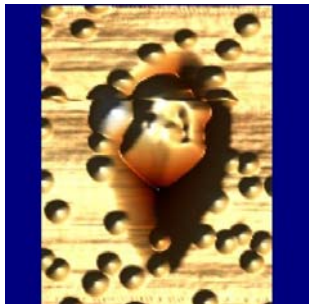
With Strain Compensating GaP MLs

Non uniform
QDs distribution

⇒ QDs Colonies

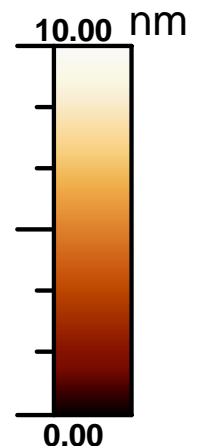


⇒ Dislocations

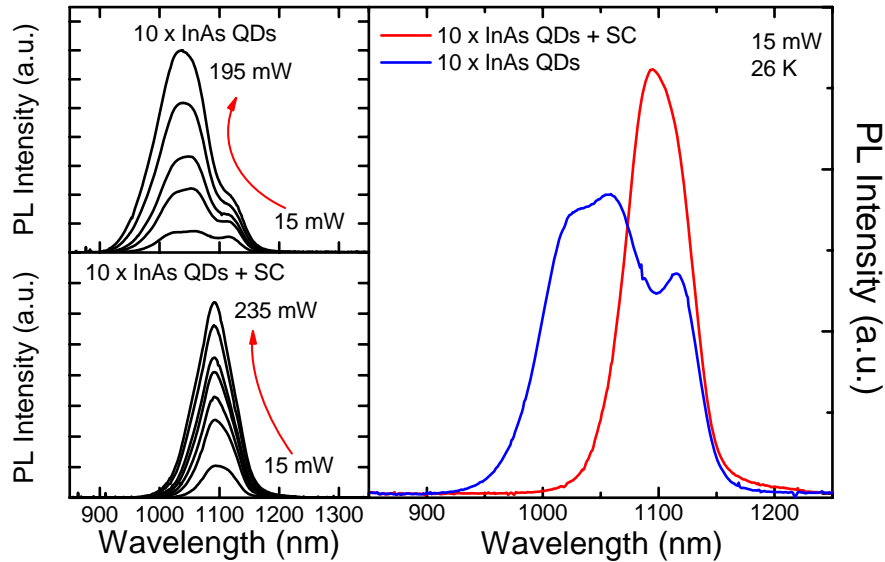


Higher uniformity
QDs Density =
 $1.7 \times 10^{10} \text{ cm}^{-2}$

Average QDs size:
- Diameter ~ 50 nm
- Height ~ 9 nm



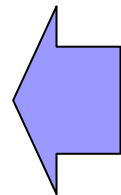
photoluminescence of 10 stacked QDs layers



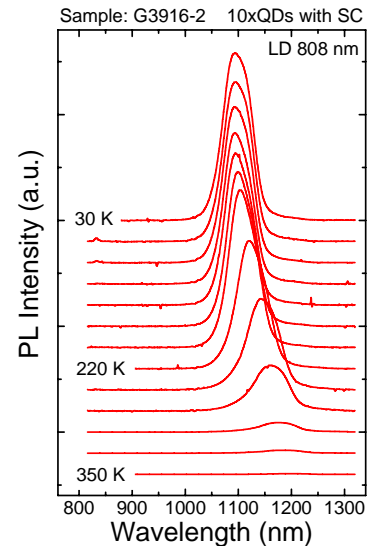
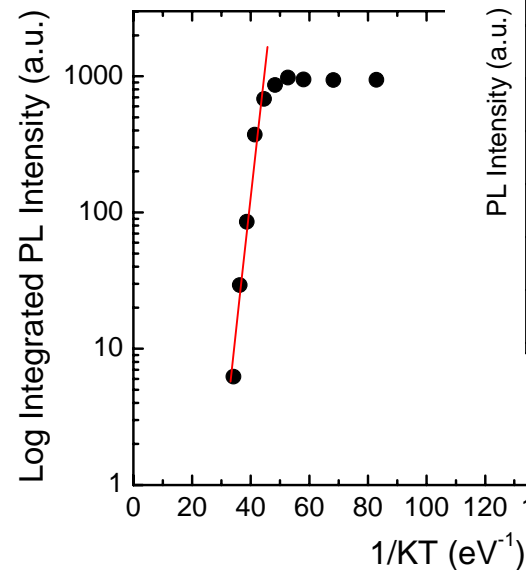
“Quasi” monomodal emission

- 1.13 eV at 26 K
- 1.05 eV at RT

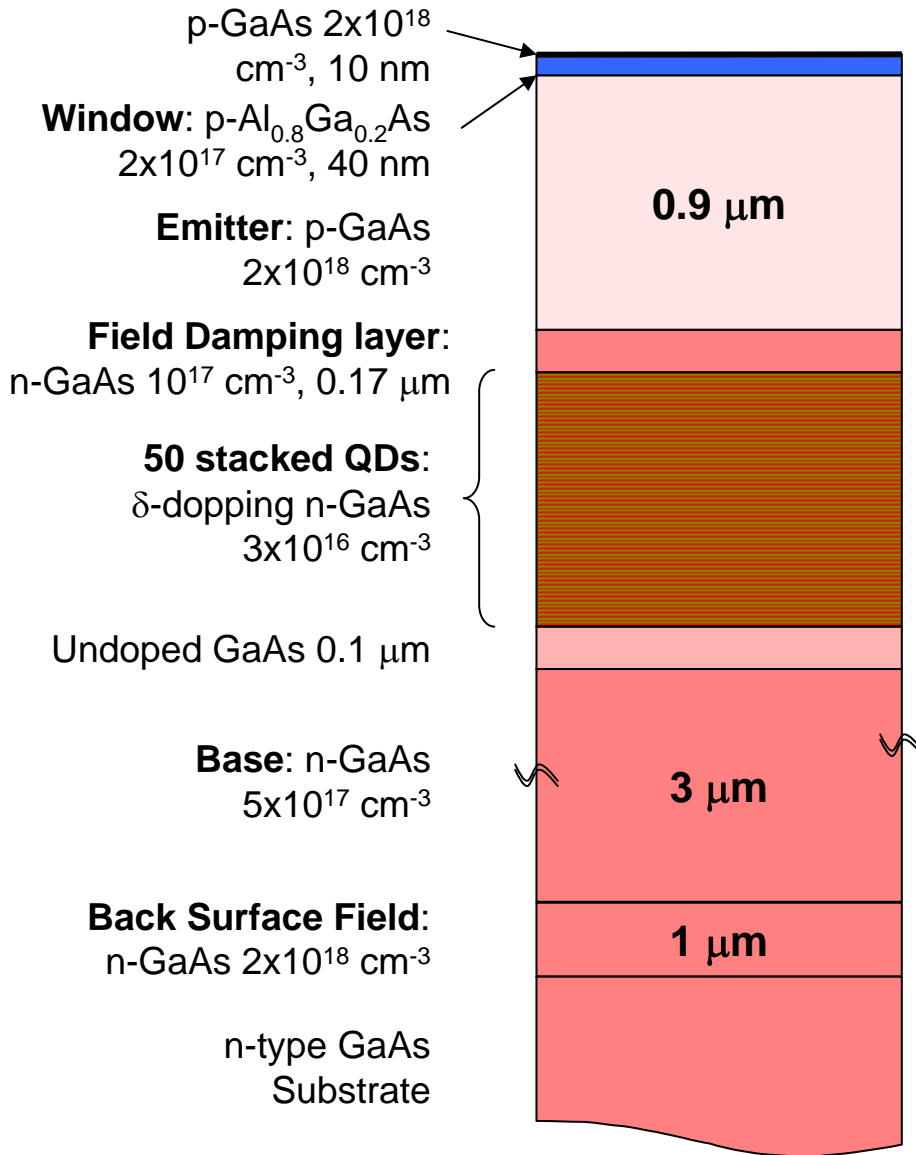
Good carrier confinement
provided by P incorporation into
the matrix



$$\Delta E_{Th} = 450 \text{ meV}$$

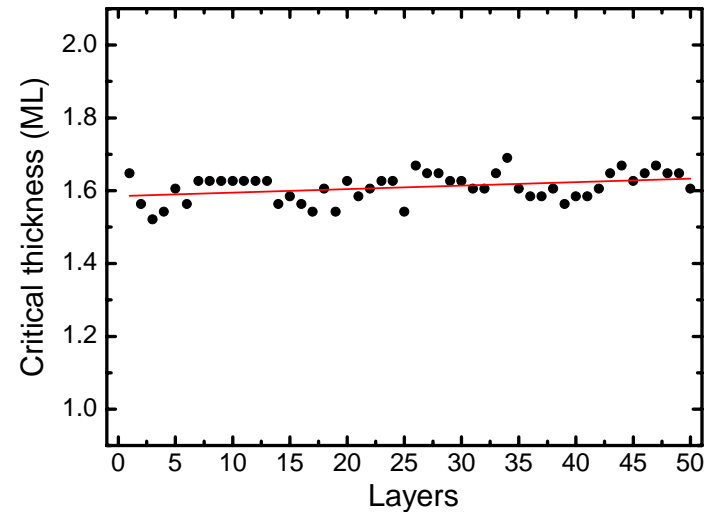


QDs Solar Cell



 50 stacked QDs layers
 18 nm of spacer

Growth by ALMBE

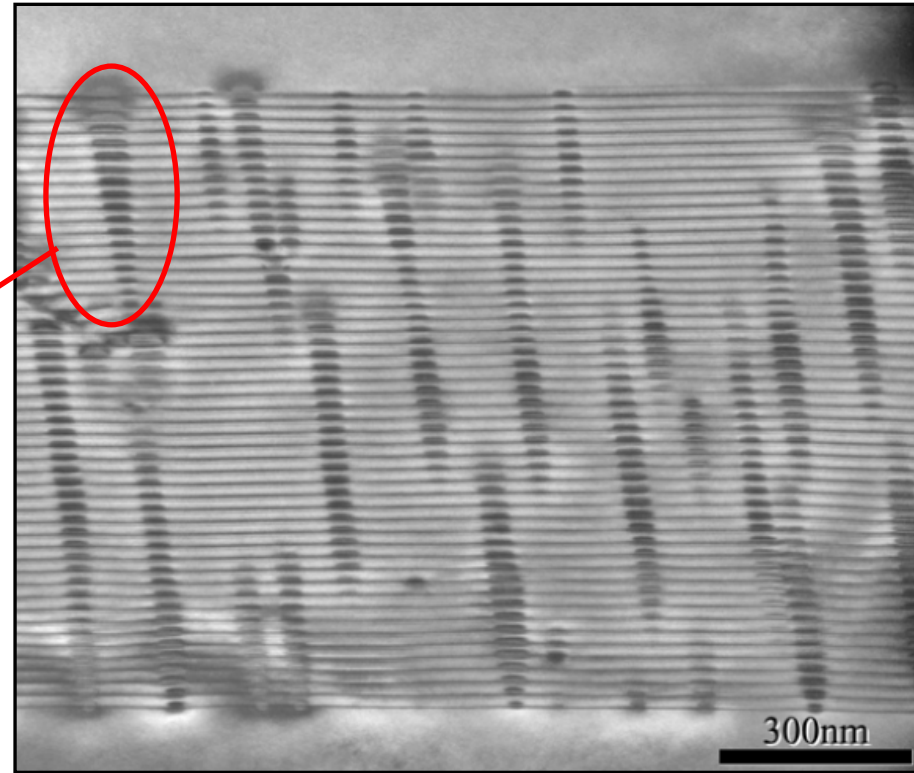
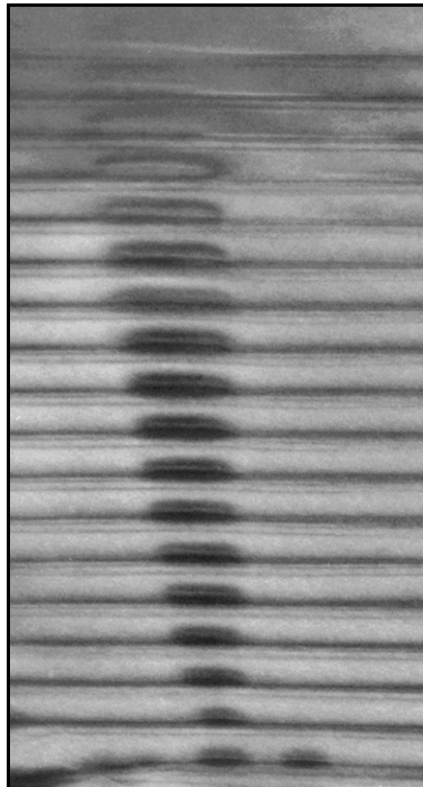
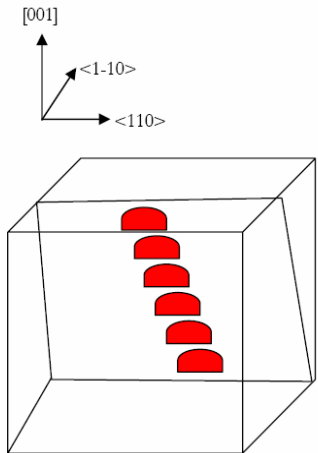


$$\theta_c = 1.61 \pm 0.04 \text{ ML}$$

50 stacked SCQDs Solar Cell: Structural characterization: TEM

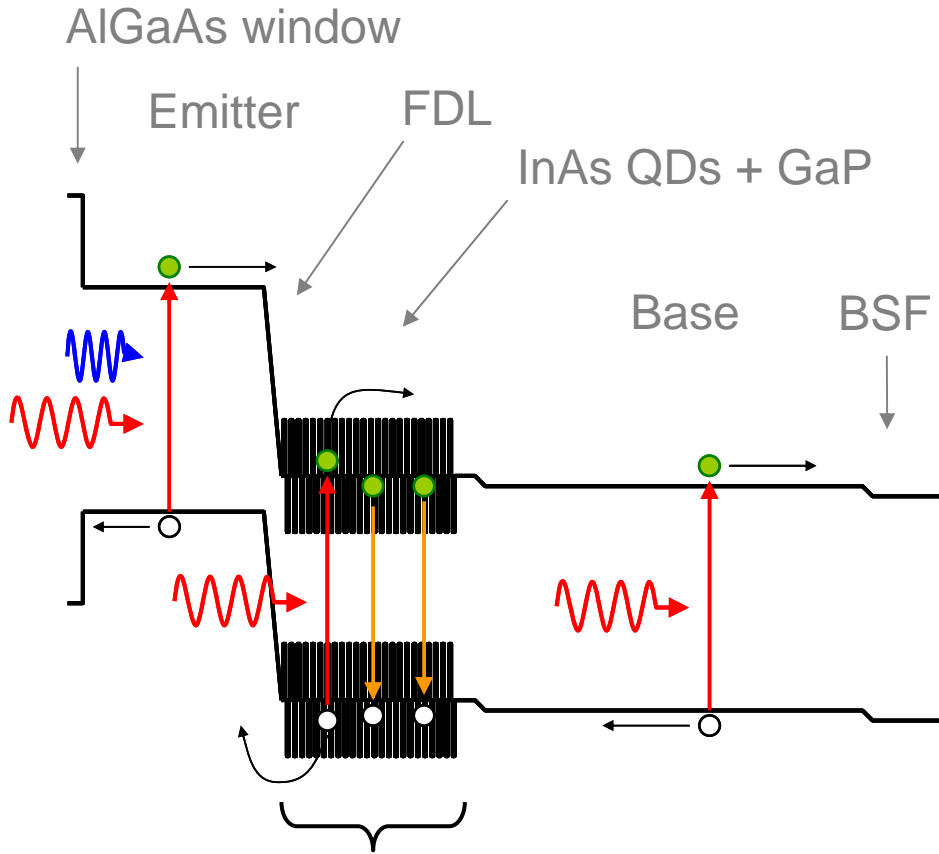
↗ Very low defect density

↗ Vertically aligned QDs

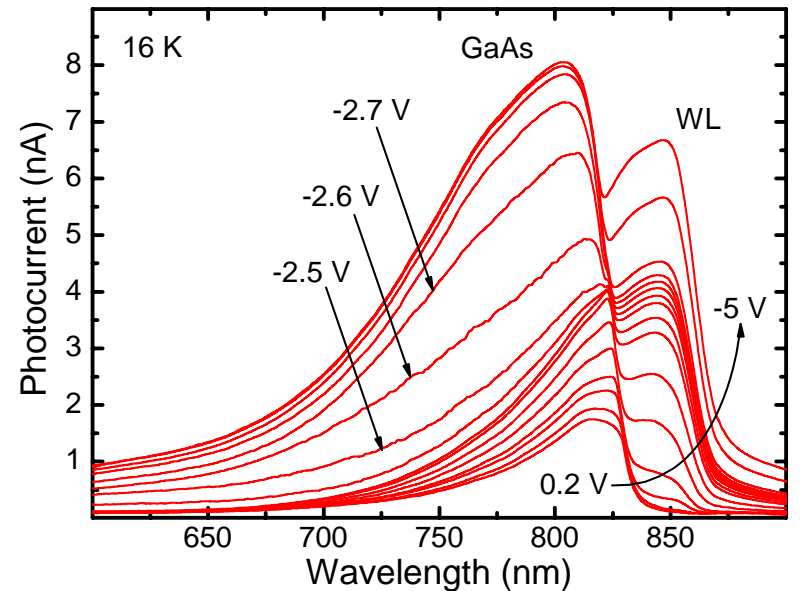
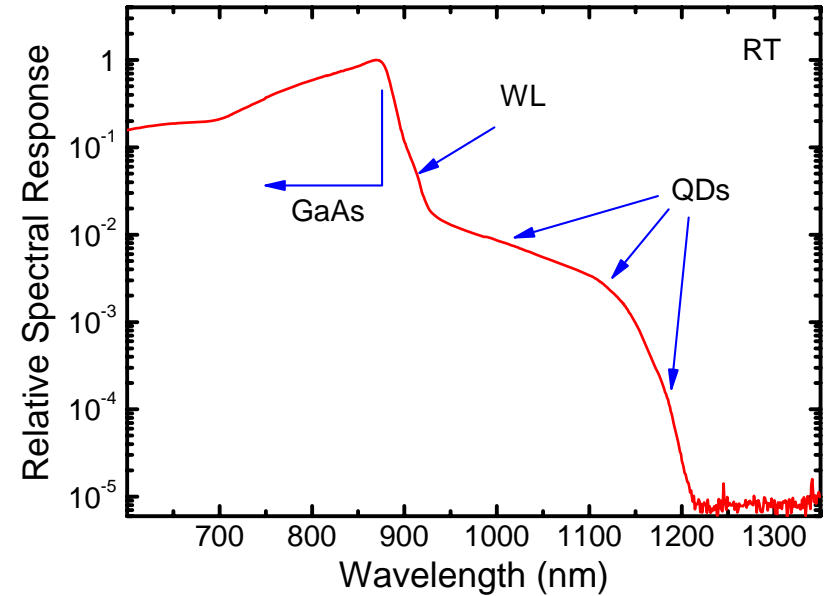


TEM $\langle 110 \rangle$ cross-section by
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50 stacked SCQDs Solar Cell: Photocurrent



- high recombination in the QDs region
- ⇒ Reduced extraction of electrons photogenerated in the emitter
- ⇒ Poor high energy response



Conclusions

- ↪ Stacks of 10 and 50 InAs QDs layers with only 18 nm of spacer have been grown using 2 ML GaP for strain compensation.
- ↪ XRD, TEM and PL experiments suggest good structural and optical quality.
- ↪ Photocurrent signal up to 1.2 μm is observed in the 50 layers solar cell due to light absorption in the nanostructures.

*Thank you
for your
attention!!!*

